

AMENDMENTS TO THE SPECIFICATION

Please amend the paragraph at page 1, lines 13-21 as follows:

Heretofore, as a technique for inspecting a plurality of conductive patterns, there has been known a contact (pin contact) method for inspecting a quality parameter, such as conduction, of the conductive patterns, which comprises bringing a plurality of pins into contact, respectively, with first and second opposite ends of the conductive patterns, supplying an electrical signal from the pins in contact with the first ends to the conductive patterns, and receiving the electrical signal from the pins in contact with the second ends, as disclosed, for example, in the following Patent Publication 1. Patent Publication 1: Japanese Patent Laid-Open Publication No. 62-269075. In the pin contact method, the electrical signal is supplied by putting a plurality of metal probes serving as the pins, respectively, on all terminals of the conductive patterns, and applying a current from the probes to the conductive patterns.

Please amend the paragraph at page 2, lines 3-10 as follows:

In that context, a contact–non-contact combinational method has also been proposed that comprises applying an inspection signal including an AC component from a plurality of pin probes in direct contact, respectively, with first ends of a plurality of conductive patterns to be inspected (a pattern to be inspected will hereinafter be referred to occasionally as "target pattern"), and detecting the inspection signal from a probe positioned in non-contact manner with

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Application No. 10/536,997

Attorney Docket No. 052644

Page 13

respect to or in spaced-apart relation to second ends of the conductive patterns by a given distance, through a capacitive coupling therebetween, as disclosed, for example, in the following

Patent Publication 2. Patent Publication 2: Japanese Laid-Open Publication No. 11-072524.

Please delete the paragraph on page 2, lines 18 and 19.